262,144 WORD ×4 BIT DYNAMIC RAM

PRELIMINARY

DESCRIPTION

The TC514258BP/BJ/BZ/BFT is the new generation dynamic RAM organized 262,144 words by 4 bits. The TC514258BP/BJ/BZ/BFT utilizes TOSHIBA's CMOS Silicon gate process technology as well as advanced circuit techniques to provide wide operating margins, both internally and to the system user. Multiplexed address inputs permit the TC514258BP/BJ/BZ/BFT to be packaged in a standard 20 pin plastic DIP, 26/20 pin plastic SOJ, 20/19 pin plastic ZIP, 24/20 pin plastic TSOP. The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment. System oriented features include single power supply of 5V±10% tolerance, direct interfacing capability with high performance logic families such as Schottky TTL.

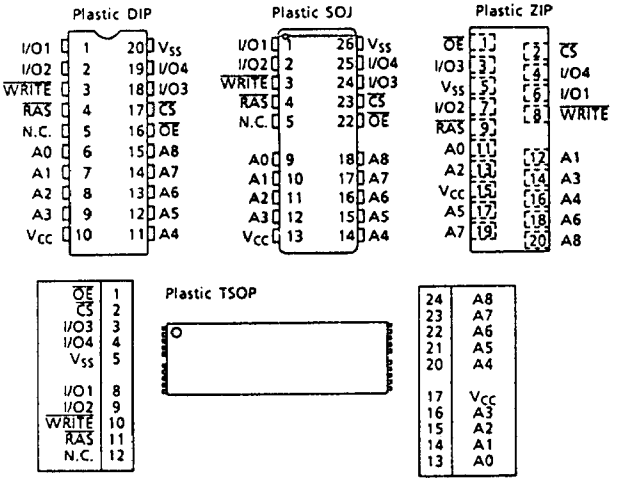
FEATURES

- 262,144 word by 4 bit organization
- Fast access time and cycle time

		TC514258BP/BJ/BZ/BFT-60
t_{RAC}	$\overline{RAS}$ Access Time	60ns
t_{AA}	Column Address Access Time	30ns
t_{CAC}	$\overline{CS}$ Access Time	20ns
t_{RC}	Cycle Time	110ns
t_{SC}	Static column Mode Cycle Time	35ns

- Single power supply of 5V±10% with a built-in V_{BB} generator
- Low Power
  495mW MAX. Operating
  5.5mW MAX. Standby
- Outputs unlatched at cycle end allows two-dimensional chip selection
- Read-Modify-Write, $\overline{CS}$ before $\overline{RAS}$ refresh, $\overline{RAS}$-only refresh, Hidden refresh, and Static Column Mode capability
- All inputs and outputs TTL compatible
- 512 refresh cycles/8ms
- Package TC514258BP : DIP20-P-300B
  TC514258BJ : SOJ26-P-300
  TC514258BZ : ZIP20-P-400
  TC514258BFT : TSOP24-P-0616

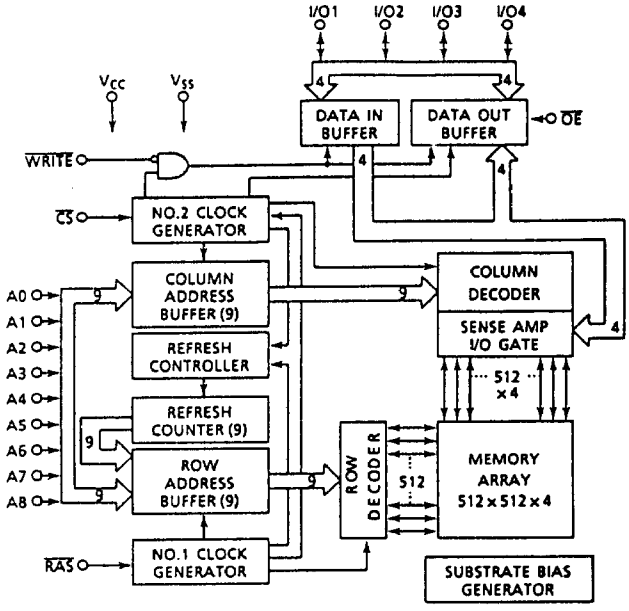
PIN CONNECTION



PIN NAMES

A0~A8	Address Inputs
$\overline{RAS}$	Row Address Strobe
$\overline{CS}$	Chip Select
$\overline{WRITE}$	Read/Write Input
$\overline{OE}$	Output Enable
I/O1~I/O4	Data Input/Output
V_{CC}	Power (+5V)
V_{SS}	Ground
N.C.	No Connection

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

ITEM	SYMBOL	RATING	UNITS	NOTES
Input Voltage	V_{IN}	−1~7	V	1
Output Voltage	V_{OUT}	−1~7	V	1
Power Supply Voltage	V_{CC}	−1~7	V	1
Operating Temperature	T_{OPR}	0~70	°C	1
Storage Temperature	T_{STG}	−55~150	°C	1
Soldering Temperature · Time	T_{SOLDER}	260 · 10	°C · sec	1
Power Dissipation	P_D	600	mW	1
Short Circuit Output Current	I_{OUT}	50	mA	1

RECOMMENDED DC OPERATING CONDITIONS (Ta = 0~70°c)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT	NOTES
V_{CC}	Supply Voltage	4.5	5.0	5.5	V	2
V_{IH}	Input High Voltage	2.4	-	6.5	V	2
V_{IL}	Input Low Voltage	−1.0	-	0.8	V	2

DC ELECTRICAL CHARACTERISTICS (VCC = 5V ± 10%, Ta = 0~70°c)

SYMBOL	PARAMETER		MIN.	MAX.	UNITS	NOTES
I_{CC1}	OPERATING CURRENT Average Power Supply Operating Current ($\overline{RAS}$, $\overline{CS}$, Address Cycling: $t_{RC} = t_{RC}$ MIN.)	TC514258BP/BJ/BZ/BFT-60	–	90	mA	3, 4, 5
I_{CC2}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS} = \overline{CS} = V_{IH}$)		–	2	mA	
I_{CC3}	$\overline{RAS}$ ONLY REFRESH CURRENT Average Power Supply Current, $\overline{RAS}$ Only Mode ($\overline{RAS}$ Cycling, $\overline{CS} = V_{IH}$: $t_{RC} = t_{RC}$ MIN.)	TC514258BP/BJ/BZ/BFT-60	–	90	mA	3, 5
I_{CC4}	STATIC COLUMN MODE CURRENT Average Power Supply Current, STATIC COLUMN Mode ($\overline{RAS} = \overline{CS} = V_{IL}$, Address Cycling: $t_{SC} = t_{SC}$ MIN.)	TC514258BP/BJ/BZ/BFT-60	–	70	mA	3, 4, 5
I_{CC5}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS} = \overline{CS} = V_{CC} - 0.2V$)		–	1	mA	
I_{CC6}	$\overline{CS}$ BEFORE $\overline{RAS}$ REFRESH CURRENT Average Power Supply Current, $\overline{CS}$ Before $\overline{RAS}$ Mode ($\overline{RAS}$, $\overline{CS}$ Cycling: $t_{RC} = t_{RC}$ MIN.)	TC514258BP/BJ/BZ/BFT-60	–	90	mA	3, 5
$I_{I(L)}$	INPUT LEAKAGE CURRENT Input Leakage Current, any input ($0V \leq V_{IN} \leq 6.5V$, All Other Pins Not Under Test = 0V)		– 10	10	μA	
$I_{O(L)}$	OUTPUT LEAKAGE CURRENT (D_{OUT} is disabled, $0V \leq V_{OUT} \leq 5.5V$)		– 10	10	μA	
V_{OH}	OUTPUT LEVEL Output "H" Level Voltage ($I_{OUT} = -5mA$)		2.4	–	V	
V_{OL}	OUTPUT LEVEL Output "L" Level Voltage ($I_{OUT} = 4.2mA$)		–	0.4	V	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(VCC = 5V ± 10%, Ta = 0~70°c) (Notes 6, 7, 8)

SYMBOL	PARAMETER	TC514258BP/BJ/BZ/BFT-60		UNIT	NOTES
		MIN.	MAX.		
t_{RC}	Random Read or Write Cycle Time	110	-	ns	
t_{RMW}	Read-Modify-Write Cycle Time	165	-	ns	
t_{SC}	Static Column Mode Cycle Time	35	-	ns	
t_{SRMW}	Static Column Mode Read-Modify-Write Cycle Time	90	-	ns	
t_{RAC}	Access Time from $\overline{RAS}$	-	60	ns	9,14
t_{CAC}	Access Time from $\overline{CS}$	-	20	ns	9,14
t_{AA}	Access Time from Column Address	-	30	ns	9,15
t_{ALW}	Access Time from Last Write	-	55	ns	9,16
t_{CLZ}	$\overline{CS}$ to output in Low-Z	0	-	ns	9
t_{OFF}	Output Buffer Turn-off Delay	0	20	ns	10
t_{AOH}	Output Data Hold Time from Column Addres	5	-	ns	
t_{OW}	Output Data Enable Time from $\overline{WRITE}$	-	20	ns	
t_T	Transition Time (Rise and Fall)	3	50	ns	8
t_{RP}	$\overline{RAS}$ Precharge Time	40	-	ns	
t_{RAS}	$\overline{RAS}$ Pulse Width	60	10,000	ns	
t_{RASC}	$\overline{RAS}$ Pulse Width (Static Column Mode)	60	100,000	ns	
t_{RSH}	$\overline{CS}$ to $\overline{RAS}$ Hold Time	20	-	ns	
t_{CSH}	$\overline{RAS}$ to $\overline{CS}$ Hold Time	60	-	ns	
t_{CS}	$\overline{CS}$ Pulse Width	20	10,000	ns	
t_{CSC}	$\overline{CS}$ Pulse Width (Static Column Mode)	20	100,000	ns	
t_{RCD}	$\overline{RAS}$ to $\overline{CS}$ Delay Time	20	40	ns	14
t_{RAD}	$\overline{RAS}$ to Column Address Delay Time	15	30	ns	15
t_{CRP}	$\overline{CS}$ to $\overline{RAS}$ Precharge Time	5	-	ns	
t_{CP}	$\overline{CS}$ Precharge Time	10	-	ns	
t_{ASR}	Row Address Set-Up Time	0	-	ns	
t_{RAH}	Row Address Hold Time	10	-	ns	
t_{ASC}	Column Address Set-Up Time	0	-	ns	
t_{CAH}	Column Address Hold Time	15	-	ns	
t_{AWR}	Column Address Hold Time referenced to $\overline{RAS}$ (WRITE CYCLE)	50	-	ns	
t_{AR}	Column Address Hold Time referenced to $\overline{RAS}$ (READ CYCLE)	85	-	ns	
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	30	-	ns	
t_{AH}	Column Address Hold Time referenced to $\overline{RAS}$ Rise	5	-	ns	17
t_{LWAD}	Last Write to Column Address Delay Time	20	25	ns	16
t_{AHLW}	Last Write to Column Address Delay Time	55	-	ns	
t_{RCS}	Read Command Set-up Time referenced to $\overline{CS}$	0	-	ns	

SYMBOL	PARAMETER	TC514258BP/BJ/BZ/BFT-60		UNITS	NOTES
		MIN.	MAX.		
t_{RCH}	Read Command Hold Time referenced to $\overline{CS}$	0	-	ns	11
t_{RRH}	Read Command Hold Time referenced to $\overline{RAS}$	0	-	ns	11
t_{WCH}	Write Command Hold Time (Output Data Disable)	10	-	ns	
t_{WCR}	Write Command Hold Time referenced to $\overline{RAS}$	45	-	ns	
t_{WP}	Write Command Pulse Width	10	-	ns	
t_{WI}	Write Command Inactive Time	10	-	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	20	-	ns	
t_{CWL}	Write Command to $\overline{CS}$ Lead Time	20	-	ns	
t_{DS}	Data-In Set-Up Time	0	-	ns	12
t_{DH}	Data-In Hold Time	15	-	ns	12
t_{DHR}	Data-In Hold Time referenced to $\overline{RAS}$	50	-	ns	
t_{REF}	Refresh Period	-	8	ms	
t_{WCS}	Write Command Set-UP Time (Output Data Disable)	0	-	ns	13
t_{CWD}	$\overline{CS}$ to $\overline{WRITE}$ Delay Time (READ-MODIFY-WRITE CYCLE)	50	-	ns	13
t_{RWD}	$\overline{RAS}$ to $\overline{WRITE}$ Delay Time (READ-MODIFY-WRITE Cycle)	90	-	ns	13
t_{AWD}	Column Address to $\overline{WRITE}$ Delay Time	60	-	ns	13
t_{CSR}	$\overline{CS}$ Set-Up Time($\overline{CS}$ before $\overline{RAS}$)	5	-	ns	
t_{CHR}	$\overline{CS}$ Hold Time($\overline{CS}$ before $\overline{RAS}$)	15	-	ns	
t_{RPC}	$\overline{RAS}$ to $\overline{CS}$ Precharge Time	0	-	ns	
t_{CPT}	$\overline{CS}$ Precharge Time ($\overline{CS}$ before $\overline{RAS}$ Counter Test Cycle)	30	-	ns	
t_{ROH}	$\overline{RAS}$ Hold Time referenced to $\overline{OE}$	10	-	ns	
t_{OEA}	$\overline{OE}$ Access Time	-	20	ns	
t_{OED}	$\overline{OE}$ to Data Delay	20	-	ns	
t_{OEZ}	Output Buffer turn off Delay Time from $\overline{OE}$	0	20	ns	10
t_{OEH}	$\overline{OE}$ Command Hold Time	20	-	ns	

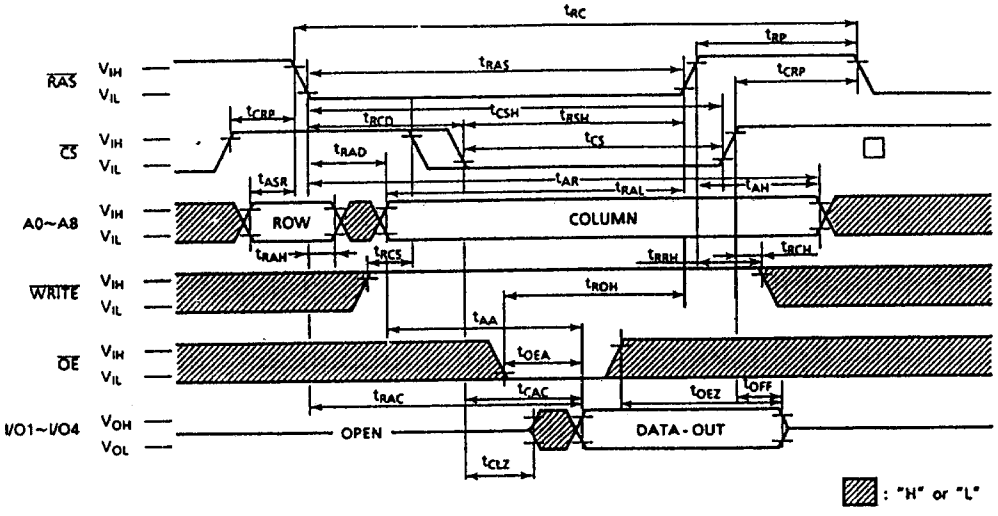
CAPACITANCE (VCC = 5V ± 10%, f = 1MHz, Ta = 0~70°c)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C_{I1}	Input Capacitance (A0~A8)	-	5	pF
C_{I2}	Input Capacitance ($\overline{RAS}$, $\overline{CS}$, $\overline{WRITE}$, $\overline{OE}$)	-	7	pF
C_O	Input/Output Capacitance (I/O1~I/O4)	-	7	pF

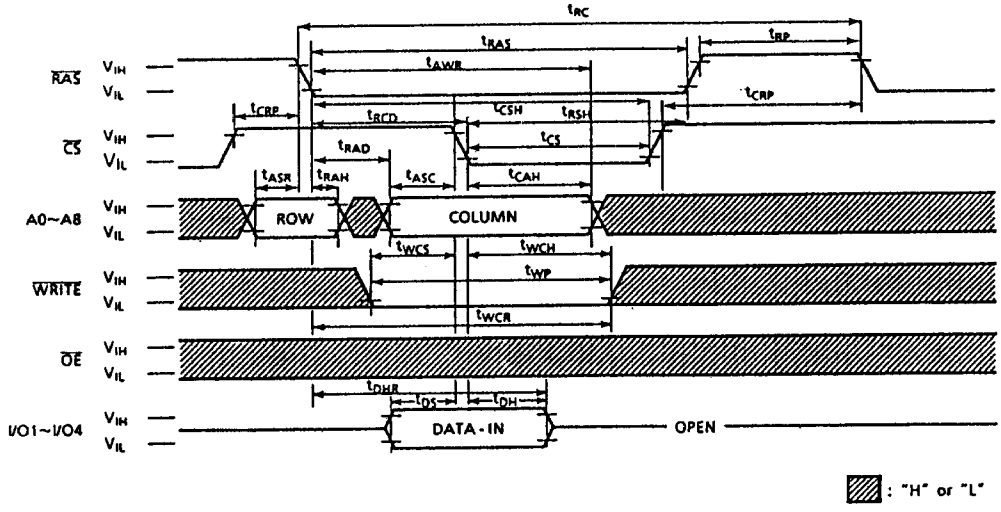
NOTES:

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.
2. All voltages are referenced to V_{SS}.
3. I_{CC1}, I_{CC3}, I_{CC4}, I_{CC6} depend on cycle rate.
4. I_{CC1}, I_{CC4} depend on output loading. Specified values are obtained with the output open.
5. Column address can be changed once or less while $\overline{RAS} = V_{IL}$.
6. An initial pause of 200μs is required after power-up followed by 8 $\overline{RAS}$ cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{CS}$ before $\overline{RAS}$ initialization cycles instead of 8 $\overline{RAS}$ cycles are required.
7. AC measurements assume $t_T = 5ns$.
8. V_{IH} (min.) and V_{IL} (max.) are reference levels for measuring timing of input signals.
9. Measured with a load equivalent to 2 TTL loads and 100pF.
10. t_{OFF} (max.) and t_{OEZ} (max.) define the time at which the output achieves the open circuit condition and are not referenced to output voltage levels.
11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
12. These parameters are referenced to $\overline{CS}$ leading edge in early write cycles and to $\overline{WRITE}$ leading edge in Read-Modify-Write cycles.
13. t_{WCS}, t_{RWD}, t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geqq t_{WCS}$ (min.), the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) through the entire cycle; If $t_{RWD} \geqq t_{RWD}$ (min.), $t_{CWD} \geqq t_{CWD}$ (min.) and $t_{AWD} \geqq t_{AWD}$ (min.) the cycle is a Read-Modify-Write cycle and the data out will contain data read from the selected cell: If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
14. Operation within the t_{RCD} (max.) limit insures that t_{RAC} (max.) can be met.
    t_{RCD} (max.) is specified as a reference point only: If t_{RCD} is greater than the specified t_{RCD} (max.) limit, then access time is controlled by t_{CAC}.
15. Operation within the t_{RAD} (max.) limit insures that t_{RAC} (max.) can be met.
    t_{RAD} (max.) is specified as a reference point only: If t_{RAD} is greater than the specified t_{RAD} (max.) limit, then access time is controlled by t_{AA}.
16. Operation within the t_{LWAD} (max.) limit insures that t_{ALW} (max.) can be met.
    t_{LWAD} (max.) is specified as a reference point only: If t_{RAD} is greater than the specified t_{LWAD} (max.) limit, then access time is controlled by t_{AA}.
17. t_{AH} is the condition to latch column address when $\overline{RAS}$ has risen up.

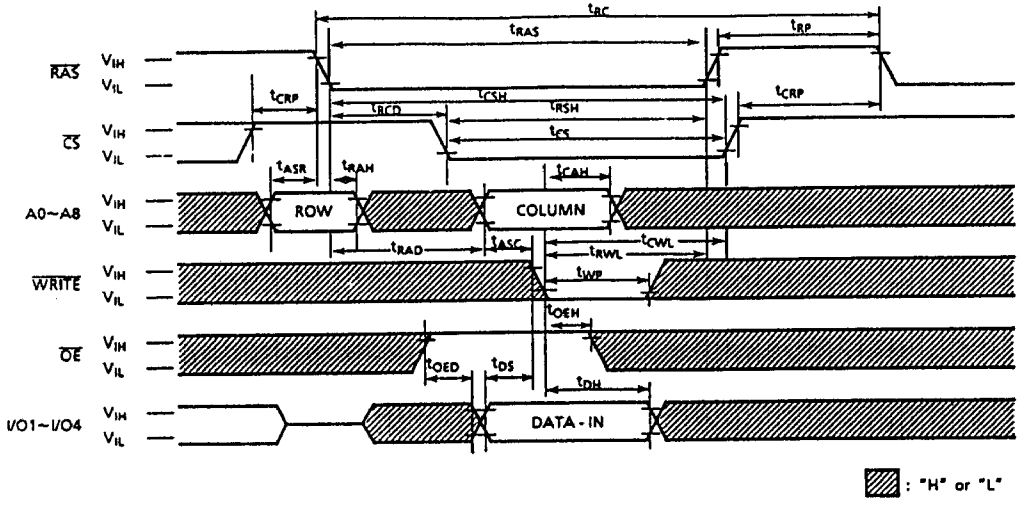
READ CYCLE



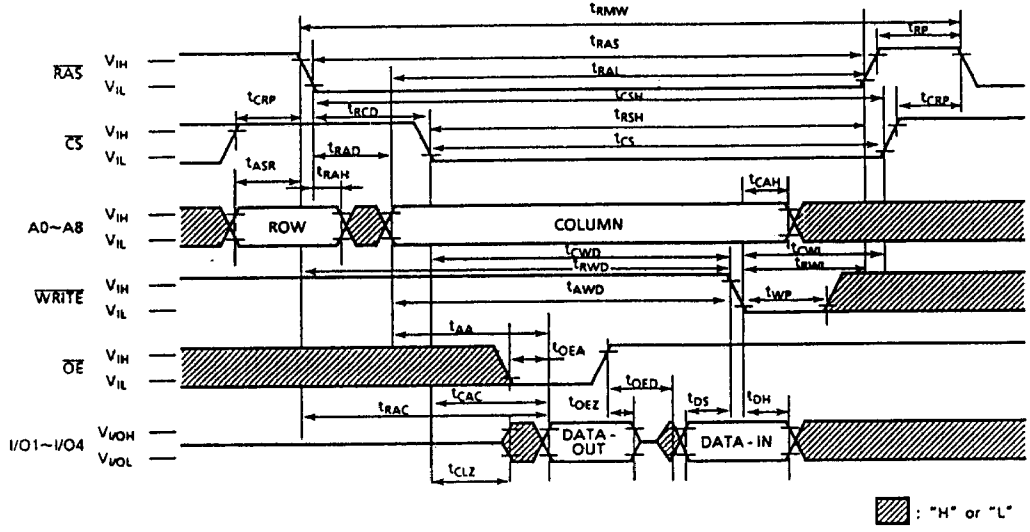
WRITE CYCLE (EARLY WRITE)



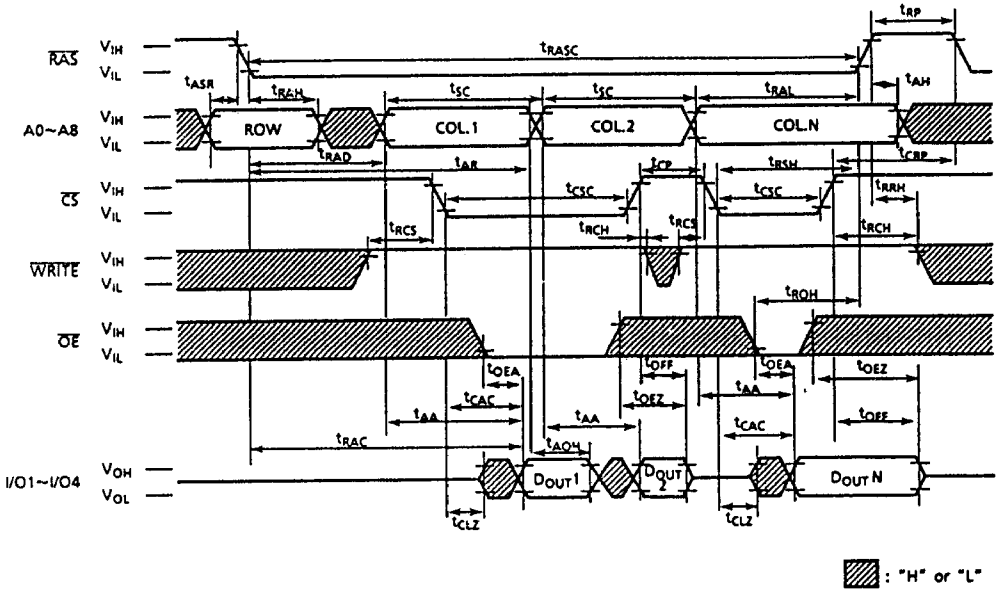
WRITE CYCLE ($\overline{OE}$ CONTROLLED WRITE)



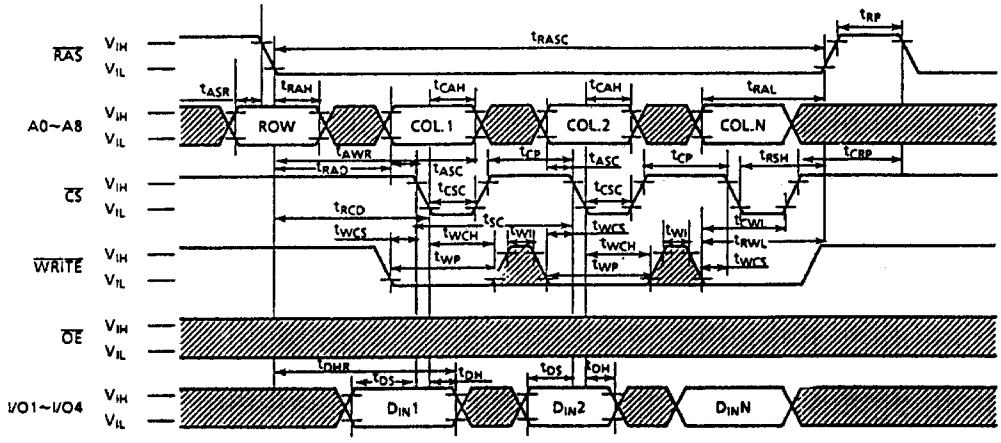
READ - MODIFY - WRITE CYCLE



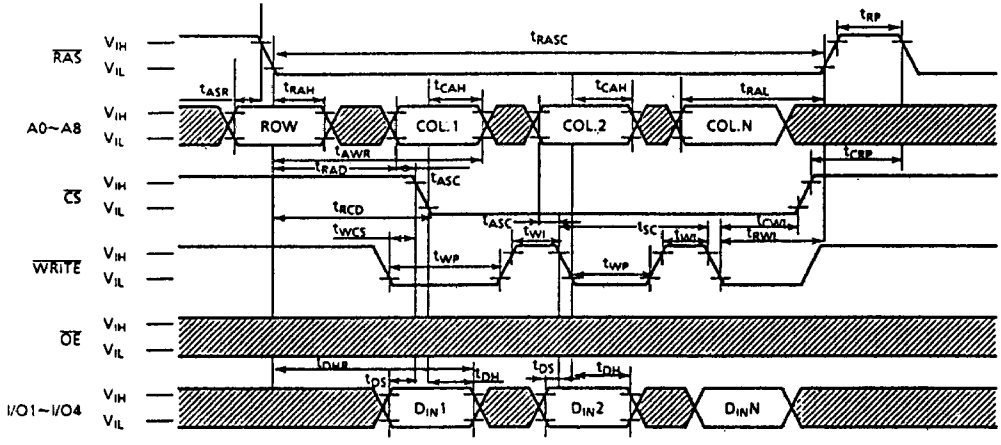
STATIC COLUMN MODE READ CYCLE



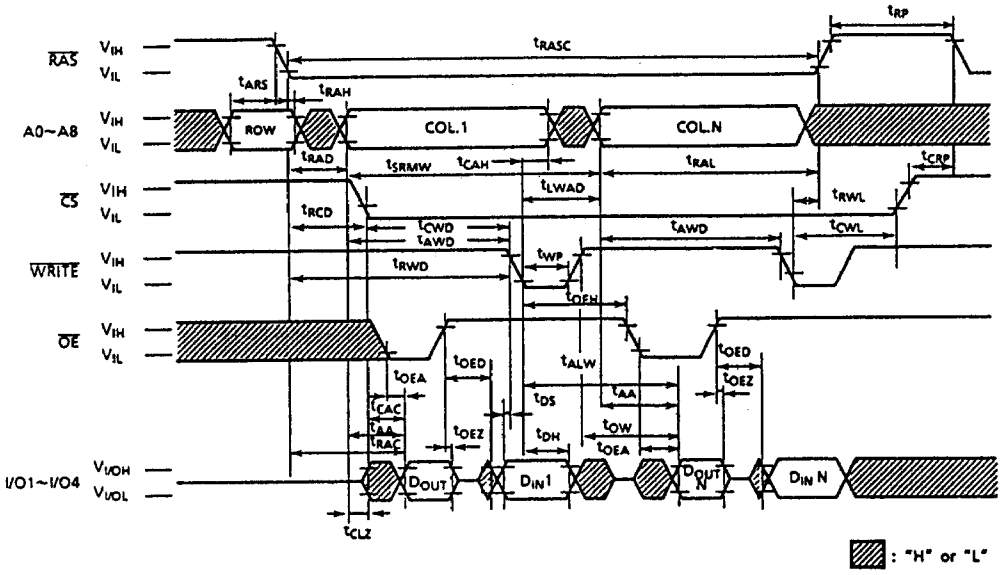
STATIC COLUMN MODE WRITE CYCLE (EARLY WRITE)



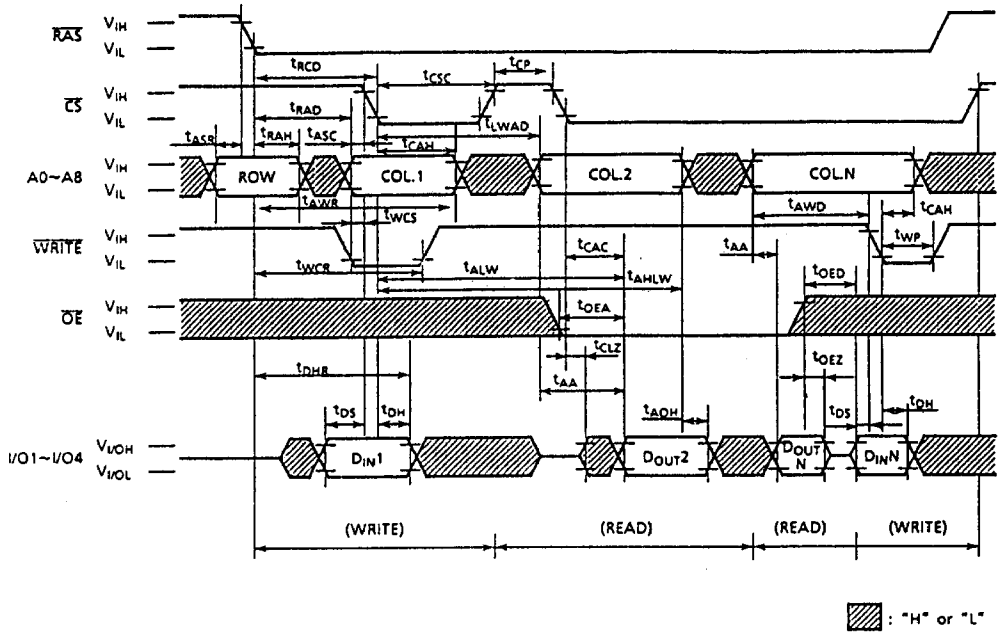
STATIC COLUMN MODE WRITE CYCLE (EARLY WRITE)



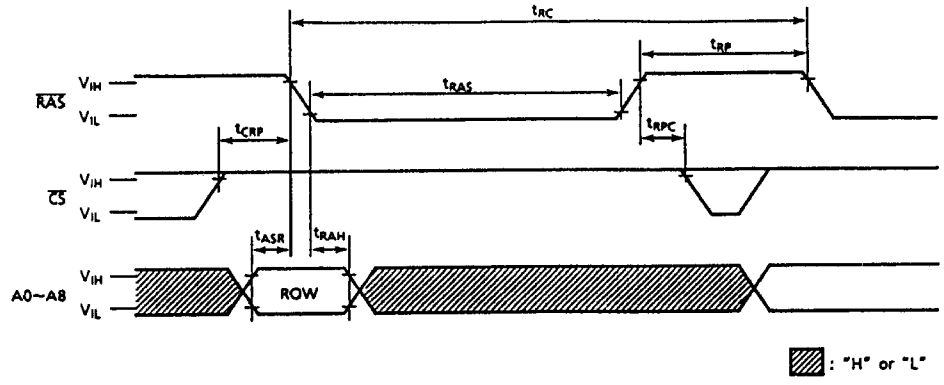
STATIC COLUMN MODE READ-MODIFY-WRITE CYCLE



STATIC COLUMN MODE READ/WRITE MIXED CYCLE

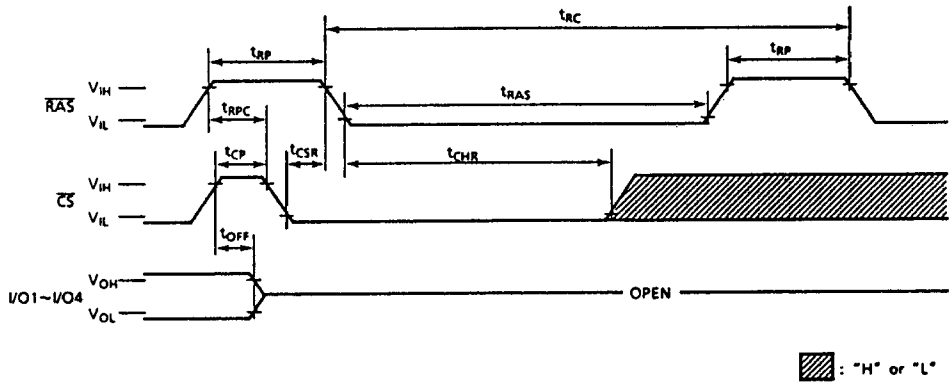


$\overline{RAS}$ ONLY REFRESH CYCLE



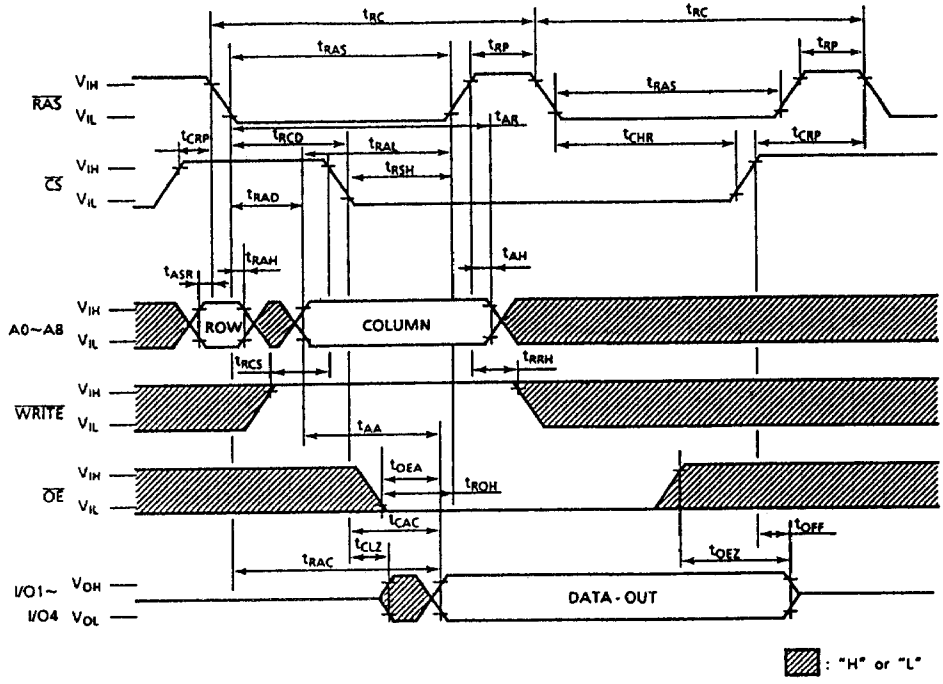
Note: WRITE, $\overline{OE}$="H" or "L"

$\overline{CS}$ BEFORE $\overline{RAS}$ REFRESH CYCLE

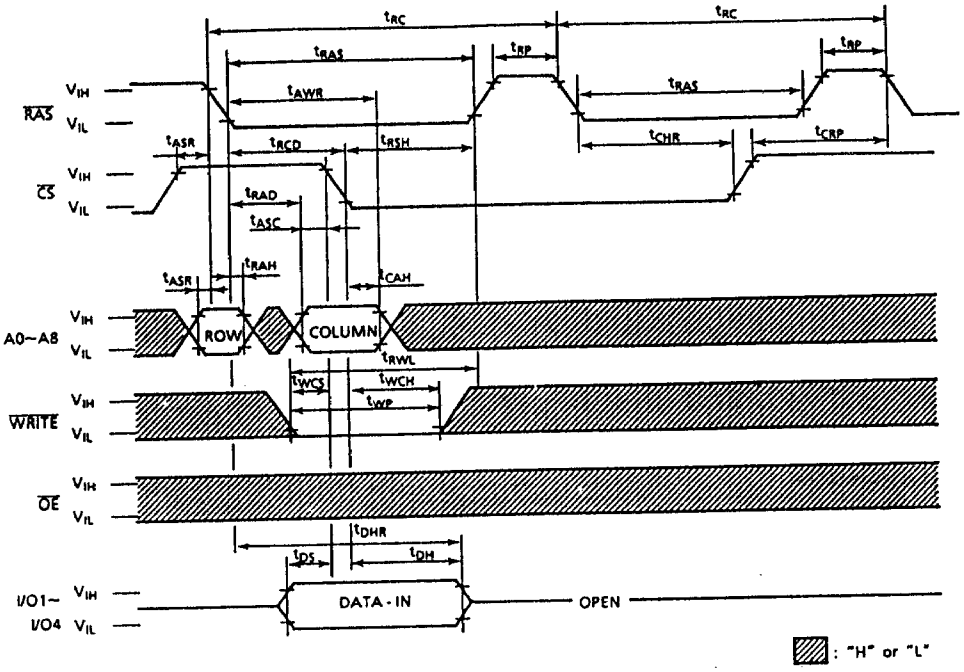


Note: WRITE, $\overline{OE}$, A0~A8="H" or "L"

HIDDEN REFRESH CYCLE (READ)



HIDDEN REFRESH CYCLE (WRITE)



$\overline{CS}$ BEFORE $\overline{RAS}$ REFRESH COUNTER TEST CYCLE